1.

Record Nr.	UNISA996385499203316
Autore	Carleton George <1559-1628.>
Titolo	A thankfull remembrance of Gods mercy [[electronic resource]] : In an historicall collection of the great and mercifull deliverances of the Church and state of England, since the Gospell began here to flourish, from the beginning of Queene Elizabeth. Collected by Geo: Carleton, Doctor of Divinitie, and Bishop of Chichester
Pubbl/distr/stampa	London, : Printed by I[ohn] D[awson] for Robert Mylbourne, and Humphrey Robinson, and are to be sold at the great south doore of Pauls, 1625
Edizione	[The second edition,]
Descrizione fisica	[16], 261, [1] p
Soggetti	Church and state - England Great Britain History Elizabeth, 1558-1603 Early works to 1800 England Church history 16th century Early works to 1800 England Church history 17th century Early works to 1800
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Printer's name from STC. With an additional title page, engraved, signed "G. Pass sc." (i.e. Willem van de Passe). The engraving by C. Danckerts, "A thankfull remembrance of Gods mercie. By G.C. The second edition", with letterpress verses and description, STC 4643.5, was possibly intended to be issued with this. Reproduction of the original in the Henry E. Huntington Library and Art Gallery.
Sommario/riassunto	eebo-0113

2.

Record Nr.	UNINA9910437802903321
Autore	Hofmann S (Siegfried)
Titolo	Auger- and x-ray photoelectron spectroscopy in materials science : a user-oriented guide / / Siegfried Hofmann
Pubbl/distr/stampa	Berlin ; ; Heidelberg, : Springer, 2012
ISBN	3-642-27381-5
Edizione	[1st ed. 2013.]
Descrizione fisica	1 online resource (543 p.)
Collana	Springer series in surface sciences ; ; 49
Disciplina	543.62
Soggetti	X-ray photoelectron spectroscopy Auger effect
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Outline of the Technique/Brief Description -- Theoretical Background -- Instrumentation -- Practical Surface Analysis with AES -- Data Evaluation/Quantification -- Problem Solving with AES (Examples).
Sommario/riassunto	To anyone who is interested in surface chemical analysis of materials on the nanometer scale, this book is prepared to give appropriate information. Based on typical application examples in materials science, a concise approach to all aspects of quantitative analysis of surfaces and thin films with AES and XPS is provided. Starting from basic principles which are step by step developed into practically useful equations, extensive guidance is given to graduate students as well as to experienced researchers. Key chapters are those on quantitative surface analysis and on quantitative depth profiling, including recent developments in topics such as surface excitation parameter and backscattering correction factor. Basic relations are derived for emission and excitation angle dependencies in the analysis of bulk material and of fractional nano-layer structures, and for both smooth and rough surfaces. It is shown how to optimize the analytical strategy, signal-to-noise ratio, certainty and detection limit. Worked examples for quantification of alloys and of layer structures in practical cases (e. g. contamination, evaporation, segregation and oxidation) are used to critically review different approaches to quantification with respect to average matrix correction factors and matrix relative sensitivity factors. State-of-the-art issues in quantitative, destructive and non-destructive

depth profiling are discussed with emphasis on sputter depth profiling and on angle resolved XPS and AES. Taking into account preferential sputtering and electron backscattering corrections, an introduction to the mixing-roughness-information depth (MRI) model and its extensions is presented. .